TOSHIBA Diode Silicon Epitaxial Planar Type

HN1D01FE

Ultra High Speed Switching Application

• HN1D02FU is composed of 2 unit of cathode common.

Low forward voltage : V_{F (3)} = 0.92V (typ.)
 Fast reverse recovery time : t_{rr} = 1.6ns (typ.)
 Small total capacitance : C_T = 2.2pF (typ.)

Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit	
Maximum (peak) reverse voltage	V_{RM}	85	V	
Reverse voltage	V _R	80	V	
Maximum (peak) forward current	I _{FM}	300*	mA	
Average forward current	I _O	100*	mA	
Surge current (10ms)	I _{FSM}	2*	Α	
Power dissipation	Р	100**	mW	
Junction temperature	Tj	150	°C	
Storage temperature	T _{stg}	-55~150	°C	

^{*:} These are the Maximum Ratings for a single diode (Q1, Q2, Q3 or Q4). Where Unit 1 and Unit 2 are used independently or simultaneously, the Maximum Ratings per diode are 75% of those for a single diode.

1. CATHODE 3. ANODE 4. CATHODE 5. CATHODE 6. ANODE ES6

1-2X1A

Weight: 0.003g (typ.)

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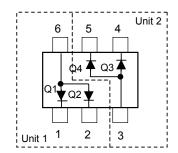
TOSHIBA

Electrical Characteristics (Q1, Q2, Q3, Q4 Common; Ta = 25°C)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Forward voltage	V _{F (1)}	_	I _F = 1mA	_	0.61	_	٧
	V _{F (2)}	_	I _F = 10mA	_	0.74	_	
	V _{F (3)}	_	I _F = 100mA	_	0.92	1.20	
Reverse current	I _{R (1)}	_	V _R = 30V	_	_	0.1	μΑ
	I _{R (2)}	_	V _R = 80V	_	_	0.5	
Total capacitance	C _T	_	V _R = 0, f = 1MHz	_	2.2	_	pF
Reverse recovery time	t _{rr}	_	I _F = 10mA (fig.1)	_	1.6	_	ns

^{**:} Total rating.

Pin Assignment (Top View)



Marking

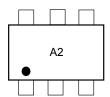
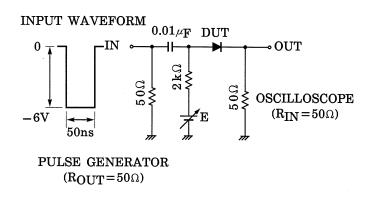
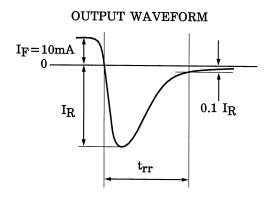
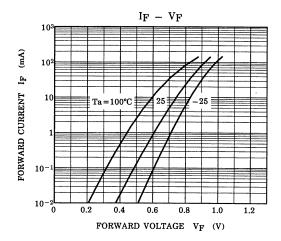
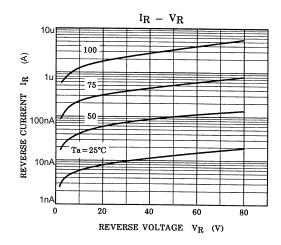


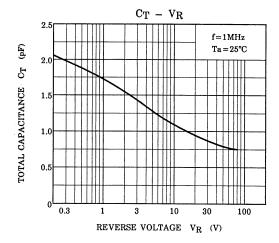
Fig. 1 Reverse Recovery Time (t_{rr}) Test Circuit

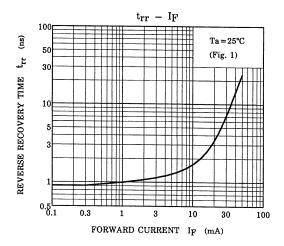












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